

<b>Notice of References Cited</b>	Application/Control No. 10/054,818	Applicant(s)/Patent Under Reexamination FUKUI ET AL.	
	Examiner Hwa C Lee	Art Unit 2672	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0032037	03-2002	Segawa, Satoko	455/517
	B	US-			
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	D	US-			
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**FOREIGN PATENT DOCUMENTS**

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